Japan Traceability Committee
Meeting Summary and Minutes

Japan Standards Summer Meetings 2013
August 6 2013, 13:00-15:00
JPR Bldg. Conference Room1, SEMI Japan Office, Tokyo, Japan

Next Committee Meeting
October 4 2013, 10:00-12:00 Japan Standard Time
Japan Standards Fall Meetings 2013, Tokyo, Japan

Committee Announcements (optional)
None

Table 1 Meeting Attendees

Co-Chairs: Yoichi Iga (Renesas Electronics), Hirokazu Tsunobuchi (Keyence)
SEMI Staff: Hirofumi Kanno

Company	*Last*	*First*	*Company*	*Last*	*First*
Renesas Electronics	Iga	Yoichi	Keyence	Tsunobuchi	Hirokazu
Fujitsu Semiconductor	Iida	Kiyokazu	Mitsubishi Electronics	Ishida	Takashi

Table 2 Leadership Changes

None

Table 3 Ballot Results (or move to Section 4, Ballot Review)

None

Table 4 Authorized Ballots (or move to Section 7, New Business)

#	*When*	*SC/TF/WG*	*Details*
5594	Cycle 7 - 2013	Japan PV Traceability Task Force	Guide for Smart Label for PV Traceability

Table 5 Authorized Activities (or move to Section 7, New Business)

None

Table 6 New Action Items (or move to Section 8, Action Item Review)

None

Table 7 Previous Meeting Actions Items **(or move to Section 8, Action item Review)**

None

1 Welcome, Reminders, and Introductions

Yoichi Iga called the meeting to order at 13:00. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

2 Review of Previous Meeting Minutes

The committee reviewed the minutes of the previous meeting.

Motion: Approve the minutes of the previous meeting
By / 2nd: Hirokazu Tsunobuchi (Keyence) / Kiyokazu Iida (Fujitsu Semiconductor)
Discussion: None
Vote: 3:0

3 Liaison Reports

3.1 *North America Traceability Committee*

Hirofumi Kanno (SEMI) reported for the North America Traceability Committee. Of note:

- Committee Structure & Leaders
- Meeting Information
  - Last meeting: July 11th, 2013 (1:00-3:00 PM), San Francisco Marriott Marquis, CA. at SEMICON West 2013
  - Next meeting: July 2014, San Francisco Marriott Marquis, CA. at SEMICON West 2014
- Ballot Results
  - Document 5581, Revision of SEMI T3-0302 (Reapproved 1108), Specification for Wafer Box Labels
    - Passed as balloted
  - Document 5582, Reapproval of SEMI T4-0301 (Reapproved 0307), Specification for 150 mm and 200 mm Pod Identification Dimensions
    - Passed as balloted
  - Document 5487A, New Standard: Specification for Basic Protocols to Support the Interoperation of Traceability Systems Necessary for Managing Product Identity throughout the Life Cycle of Objects Using Digital Signatures and Time Stamps
    - Failed and returned to Task Force
- New TFOF/SNARF
  - New SNARFs
    - Doc. 5612, Reapproval of SEMI T7-0303 (Reapproved 0709), Specification for Back Surface Marking of Double-Side Polished Wafers with a Two-Dimensional Matrix Code Symbol
    - Doc. 5613, Reapproval of SEMI T11-0703 (Reapproved 0709), Specification for Marking of Hard Surface Reticle Substrates
    - Doc. 5614, Revision of SEMI T3-0302 (Reapproved 1108), Specification for Wafer Box Labels
      - To address a previous ballot comment by proposing additional symbologies (QR code).
- Upcoming Ballots
  - Cycle 1-2014 for review at SEMICON West
    - Doc. 5612, Reapproval of SEMI T7-0303 (Reapproved 0709), Specification for Back Surface Marking of Double-Side Polished Wafers with a Two-Dimensional Matrix Code Symbol
    - Doc. 5613, Reapproval of SEMI T11-0703 (Reapproved 0709), Specification for Marking of Hard Surface Reticle Substrates
    - Doc. 5614, Revision of SEMI T3-0302 (Reapproved 1108), Specification for Wafer Box Labels

- Meeting
  - The NA Traceability is in the maintenance mode.
  - The next NA Traceability committee will be at SEMICON West 2014
- Japan Proposal
  - JA Proposal to Traceability Charter Changes
    - The NA Traceability Committee is Not supporting the revised charter due to beyond the scope of SEMI.
  - Document 5594 New Standard: Guide For Smart Label For PV Traceability
    - This scope of this document is too broad. It involves with the entire PV system. NA would like Japan to make significant revision for this document.

Attachment: 01, NA Traceability Liaison Report20130719

3.2 *450mm Notch Free Wafer Updates from Silicon Wafer Committee*

None

3.3 *SEMI Staff Report*

Hirofumi Kanno (SEMI) gave the SEMI Staff Report. Of note:

- Global SEMI Events
- Global Standards Meetings Schedule
- Ballot Critical Dates
- Publication Update
- ISC A&R SC Summary May and June 2013
- Preparation for SEMICON Japan 2013
- Contact Information

Attachment: 02, SEMI Staff Report 2013 July R0.2a

4 Subcommittee & Task Force Reports

4.1 5 Year Review Task Force

Hirokazu Tsunobuchi (Keyence) reported there was no update for the Task Force.

4.2 Japan PV Traceability Task Force

Yoichi Iga (Renesas Electronics) reported below.

- The Task Force reviewed Doc. 5487A result which the previous North America Traceability Committee adjudicated at SEMICON West 2013.
- The Task Force prepared Doc.5594 for *New Standards: Guide for Smart Label for PV Traceability*.

Kiyokazu Iida (Fujitsu Semiconductor) submitted the draft Doc. 5594 for its ballot issuance.

Motion: Approve the ballot issuance of Doc. 5594 in Cycle 7

By / 2nd: Hirokazu Tsunobuchi (Keyence) / Kiyokazu Iida (Fujitsu Semiconductor)

Discussion: The attendees in the committee reviewed and discussed their inputs/comments for Doc. 5595 from North America Traceability Committee stated on the Liaison report. Since the Task Force members would like the North America members to clear their technical reasons for issues of Doc. 5594, the members decided to issue the ballot in Cycle 7, 2013.

Vote: 3:0

Attachment: 03, JA PV Traceability TF Report

5 Old Business

5.1 Disbandment of the Japan Anti-Counterfeiting Task Force

Hirofumi Kanno (SEMI) addressed the committee on this topic.

6 New Business

None

7 Action Item Review

7.1 *Open Action Items*

None

7.2 *New Action Items*

None

8 Next Meeting and Adjournment

The next meeting of the Japan Traceability committee is scheduled for October 4 at Japan Standards Fall Meetings 2013 in SEMI Japan office, Tokyo, Japan.

Respectfully submitted by:
Hirofumi Kanno
Manager
SEMI Japan
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Minutes approved by:

Yoichi Iga (Renesas Electronics), Co-chair	<Date approved>
Hirokazu Tsunobuchi (Keyence), Co-chair	<Date approved>

Table 8 Index of Available Attachments [#1]

#	*Title*	#	*Title*
01	NA Traceability Liaison Report20130719		
02	SEMI Staff Report 2013 July R0.2a		
03	03_JA PV Traceability TF Report		

#1 Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org. For additional information or to obtain individual attachments, please contact [SEMI Staff Name] at the contact information above.